Docket No.

**2**12881US-252**43**7-2

IN RE APPLICATION ADEMA Eiji YOSHIDA

SERIAL NO:

09/931,104

FILED:

August 17, 2001

FOR:

SEMICONDUCTOR DEVICE AND METHOD OF ANALYZING SAME

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR:

Transmitted herewith is an amendment in the above-identified application.

- No additional fee is required
- ☐ Small entity status of this application under 37 C.F.R. §1.9 and §1.27 is claimed.
- Additional documents filed herewith: Marked-up Copy

The Fee has been calculated as shown below:

CLAIMS	CLAIMS REMAINING		HIGHEST NUMBER PREVIOUSLY PAID	NO. EXTRA , CLAIMS	R	ATE		CALCULATIONS
TOTAL	17	MINUS	20	0	x :	\$18	=	\$0.00
INDEPENDENT	1	MINUS	3 .	. 0	x S	\$84	=	\$0.00
		☐ MULTIPLE DEPENDENT CLAIMS + \$280 =				\$0.00		
			TOTAL OF	ABOVE CAI	CULA	OITA	NS	\$0.00
☐ Reduction by 50% for filing by Small Entity							\$0.00	
		☐ Recordatio	n of Assignment		+ :	\$40	=	\$0.00
						TOT	AL	\$0.00

$\Box$	A check in the amount of	\$0.00	is attached

- Please charge any additional Fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.
- ☑ If these papers are not considered timely filed by the Patent and Trademark Office, then a petition is hereby made under 37 C.F.R. §1.136, and any additional fees required under 37 C.F.R. §1.136 for any necessary extension of time may be charged to Deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

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H9 Andt 12/6/02 ares

## IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF:

EIJI YOSHIDA

: EXAMINER: JOHANNES P. MONDT

SERIAL NO: 09/931,104

FILED: AUGUST 17, 2001

: GROUP ART UNIT: 2826

FOR: SEMICONDUCTOR DEVICE AND

METHOD OF ANALYZING SAME

## **SUPPLEMENTAL AMENDMENT**

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR:

Supplemental to the October 03, 2002 amendment and in response to the Office Action dated July 3, 2002, please amend the above-identified application as follows:

## IN THE CLAIMS

Please amend claims 1, 6, and 11 as shown in the Attachment, in which underlining and bracketing show the changes introduced into the previously-pending claims to arrive at the clean claims provided below:

- 1. (Twice Amended) A semiconductor device, comprising:
- a) a second MOS transistor, including a portion measured by fluctuation in potential;
- b) a wire having a first end and a second end, the second end being connected with said portion measured; and
- c) an observation part including a pn junction irradiated with a laser beam to detect said fluctuation in potential, wherein: